

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10659593	LEE, BAEK-WOON
	<b>Examiner</b>	<b>Art Unit</b>
	Sherman, Stephen G	2629

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
345	88,600,603-605,613,87-102	11/29/2006	SS
349	56,82,84,109,143	11/29/2006	SS
349	139	4/16/2007	SS

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
See attached search history		
Search Updated	11/29/2006	SS
Search Updated	4/16/2007	SS

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>